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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Discontinued at Digi-Key
Core Processor	ARM® Cortex®-M0+
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, I ² C, IrDA, LINbus, SmartCard, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, I ² S, LCD, POR, PWM, WDT
Number of I/O	50
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.8V
Data Converters	A/D 12bit SAR; D/A 12bit
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-TQFP
Supplier Device Package	64-TQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm32tg11b520f128gq64-ar

1. Feature List

The EFM32TG11 highlighted features are listed below.

- **ARM Cortex-M0+ CPU platform**
 - High performance 32-bit processor @ up to 48 MHz
 - Memory Protection Unit
 - Wake-up Interrupt Controller
- **Flexible Energy Management System**
 - 37 μ A/MHz in Active Mode (EM0)
 - 1.30 μ A EM2 Deep Sleep current (8 kB RAM retention and RTCC running from LFRCO)
- **Integrated DC-DC buck converter**
- **Backup Power Domain**
 - RTCC and retention registers in a separate power domain, available in all energy modes
 - Operation from backup battery when main power absent/insufficient
- **Up to 128 kB flash program memory**
- **Up to 32 kB RAM data memory**
- **Communication Interfaces**
 - CAN Bus Controller
 - Version 2.0A and 2.0B up to 1 Mbps
 - 4 \times Universal Synchronous/Asynchronous Receiver/ Transmitter
 - UART/SPI/SmartCard (ISO 7816)/IrDA/I2S/LIN
 - Triple buffered full/half-duplex operation with flow control
 - Ultra high speed (24 MHz) operation on one instance
 - 1 \times Universal Asynchronous Receiver/ Transmitter
 - 1 \times Low Energy UART
 - Autonomous operation with DMA in Deep Sleep Mode
 - 2 \times I²C Interface with SMBus support
 - Address recognition in EM3 Stop Mode
- **Up to 67 General Purpose I/O Pins**
 - Configurable push-pull, open-drain, pull-up/down, input filter, drive strength
 - Configurable peripheral I/O locations
 - 5 V tolerance on select pins
 - Asynchronous external interrupts
 - Output state retention and wake-up from Shutoff Mode
- **Up to 8 Channel DMA Controller**
- **Up to 8 Channel Peripheral Reflex System (PRS) for autonomous inter-peripheral signaling**
- **Hardware Cryptography**
 - AES 128/256-bit keys
 - ECC B/K163, B/K233, P192, P224, P256
 - SHA-1 and SHA-2 (SHA-224 and SHA-256)
 - True Random Number Generator (TRNG)
- **Hardware CRC engine**
 - Single-cycle computation with 8/16/32-bit data and 16-bit (programmable)/32-bit (fixed) polynomial
- **Security Management Unit (SMU)**
 - Fine-grained access control for on-chip peripherals
- **Integrated Low-energy LCD Controller with up to 8 \times 32 segments**
 - Voltage boost, contrast and autonomous animation
 - Patented low-energy LCD driver
- **Ultra Low-Power Precision Analog Peripherals**
 - 12-bit 1 Msamples/s Analog to Digital Converter (ADC)
 - On-chip temperature sensor
 - 2 \times 12-bit 500 ksamples/s Digital to Analog Converter (VDAC)
 - Up to 2 \times Analog Comparator (ACMP)
 - Up to 4 \times Operational Amplifier (OPAMP)
 - Robust current-based capacitive sensing with up to 38 inputs and wake-on-touch (CSEN)
 - Up to 62 GPIO pins are analog-capable. Flexible analog peripheral-to-pin routing via Analog Port (APORT)
 - Supply Voltage Monitor

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4.1.7 Wake Up Times

Table 4.9. Wake Up Times

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Wake up time from EM1	t_{EM1_WU}		—	3	—	AHB Clocks
Wake up from EM2	t_{EM2_WU}	Code execution from flash	—	10.1	—	μs
		Code execution from RAM	—	3.1	—	μs
Wake up from EM3	t_{EM3_WU}	Code execution from flash	—	10.1	—	μs
		Code execution from RAM	—	3.1	—	μs
Wake up from EM4H ¹	t_{EM4H_WU}	Executing from flash	—	88	—	μs
Wake up from EM4S ¹	t_{EM4S_WU}	Executing from flash	—	282	—	μs
Time from release of reset source to first instruction execution	t_{RESET}	Soft Pin Reset released	—	50	—	μs
		Any other reset released	—	352	—	μs
Power mode scaling time	t_{SCALE}	VSCALE0 to VSCALE2, HFCLK = 19 MHz ^{4 2}	—	31.8	—	μs
		VSCALE2 to VSCALE0, HFCLK = 19 MHz ³	—	4.3	—	μs

Note:

1. Time from wake up request until first instruction is executed. Wakeup results in device reset.
2. VSCALE0 to VSCALE2 voltage change transitions occur at a rate of 10 mV/ μs for approximately 20 μs . During this transition, peak currents will be dependent on the value of the DECOUPLE output capacitor, from 35 mA (with a 1 μF capacitor) to 70 mA (with a 2.7 μF capacitor).
3. Scaling down from VSCALE2 to VSCALE0 requires approximately 2.8 μs + 29 HFCLKs.
4. Scaling up from VSCALE0 to VSCALE2 requires approximately 30.3 μs + 28 HFCLKs.

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output fall time, From 70% to 30% of V _{IO}	t _{IOOF}	C _L = 50 pF, DRIVESTRENGTH ¹ = STRONG, SLEWRATE ¹ = 0x6	—	1.8	—	ns
		C _L = 50 pF, DRIVESTRENGTH ¹ = WEAK, SLEWRATE ¹ = 0x6	—	4.5	—	ns
Output rise time, From 30% to 70% of V _{IO}	t _{IOOR}	C _L = 50 pF, DRIVESTRENGTH ¹ = STRONG, SLEWRATE = 0x6 ¹	—	2.2	—	ns
		C _L = 50 pF, DRIVESTRENGTH ¹ = WEAK, SLEWRATE ¹ = 0x6	—	7.4	—	ns
Note: 1. In GPIO_Pn_CTRL register.						

4.1.12 Voltage Monitor (VMON)

Table 4.19. Voltage Monitor (VMON)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Supply current (including I _{SENSE})	I _{VMON}	In EM0 or EM1, 1 supply monitored, T ≤ 85 °C	—	6.3	TBD	μA
		In EM0 or EM1, 4 supplies monitored, T ≤ 85 °C	—	12.5	TBD	μA
		In EM2, EM3 or EM4, 1 supply monitored and above threshold	—	62	—	nA
		In EM2, EM3 or EM4, 1 supply monitored and below threshold	—	62	—	nA
		In EM2, EM3 or EM4, 4 supplies monitored and all above threshold	—	99	—	nA
		In EM2, EM3 or EM4, 4 supplies monitored and all below threshold	—	99	—	nA
Loading of monitored supply	I _{SENSE}	In EM0 or EM1	—	2	—	μA
		In EM2, EM3 or EM4	—	2	—	nA
Threshold range	V _{VMON_RANGE}		1.62	—	3.4	V
Threshold step size	N _{VMON_STESP}	Coarse	—	200	—	mV
		Fine	—	20	—	mV
Response time	t _{VMON_RES}	Supply drops at 1V/μs rate	—	460	—	ns
Hysteresis	V _{VMON_HYST}		—	26	—	mV

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Supply current, continuous conversions, WARMUP-MODE=KEEPCSENWARM	I _{CSEN_ACTIVE}	SAR or Delta Modulation conversions of 33 pF capacitor, CS0CG=0 (Gain = 10x), always on	—	90.5	—	μA
HFPERCLK supply current	I _{CSEN_HFPERCLK}	Current contribution from HFPERCLK when clock to CSEN block is enabled.	—	2.25	—	μA/MHz

Note:

- Current is specified with a total external capacitance of 33 pF per channel. Average current is dependent on how long the module is actively sampling channels within the scan period, and scales with the number of samples acquired. Supply current for a specific application can be estimated by multiplying the current per sample by the total number of samples per period ($\text{total_current} = \text{single_sample_current} * (\text{number_of_channels} * \text{accumulation})$).

4.1.19 Pulse Counter (PCNT)

Table 4.26. Pulse Counter (PCNT)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Input frequency	F_{IN}	Asynchronous Single and Quadrature Modes	—	—	20	MHz
		Sampled Modes with Debounce filter set to 0.	—	—	8	kHz

4.1.20 Analog Port (APORT)

Table 4.27. Analog Port (APORT)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Supply current ^{2 1}	I_{APORT}	Operation in EM0/EM1	—	7	—	μA
		Operation in EM2/EM3	—	915	—	nA

Note:

1. Specified current is for continuous APORT operation. In applications where the APORT is not requested continuously (e.g. periodic ACMP requests from LESENSE in EM2), the average current requirements can be estimated by multiplying the duty cycle of the requests by the specified continuous current number.
2. Supply current increase that occurs when an analog peripheral requests access to APORT. This current is not included in reported module currents. Additional peripherals requesting access to APORT do not incur further current.

4.1.21 I2C

4.1.21.1 I2C Standard-mode (Sm)¹

Table 4.28. I2C Standard-mode (Sm)¹

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
SCL clock frequency ²	f _{SCL}		0	—	100	kHz
SCL clock low time	t _{LOW}		4.7	—	—	μs
SCL clock high time	t _{HIGH}		4	—	—	μs
SDA set-up time	t _{SU_DAT}		250	—	—	ns
SDA hold time ³	t _{HD_DAT}		100	—	3450	ns
Repeated START condition set-up time	t _{SU_STA}		4.7	—	—	μs
(Repeated) START condition hold time	t _{HD_STA}		4	—	—	μs
STOP condition set-up time	t _{SU_STO}		4	—	—	μs
Bus free time between a STOP and START condition	t _{BUF}		4.7	—	—	μs

Note:

1. For CLHR set to 0 in the I2Cn_CTRL register.
2. For the minimum HPPERCLK frequency required in Standard-mode, refer to the I2C chapter in the reference manual.
3. The maximum SDA hold time (t_{HD_DAT}) needs to be met only when the device does not stretch the low time of SCL (t_{LOW}).

4.1.22 USART SPI

SPI Master Timing

Table 4.31. SPI Master Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
SCLK period ^{1 3 2}	t_{SCLK}		$2 * t_{H\overline{F}PERCLK}$	—	—	ns
CS to MOSI ^{1 3}	t_{CS_MO}		-19.8	—	18.9	ns
SCLK to MOSI ^{1 3}	t_{SCLK_MO}		-10	—	14.5	ns
MISO setup time ^{1 3}	t_{SU_MI}	IOVDD = 1.62 V	75	—	—	ns
		IOVDD = 3.0 V	40	—	—	ns
MISO hold time ^{1 3}	t_{H_MI}		-10	—	—	ns

Note:

1. Applies for both CLKPHA = 0 and CLKPHA = 1 (figure only shows CLKPHA = 0).
2. $t_{H\overline{F}PERCLK}$ is one period of the selected H \overline{F} PERCLK.
3. Measurement done with 8 pF output loading at 10% and 90% of V_{DD} (figure shows 50% of V_{DD}).

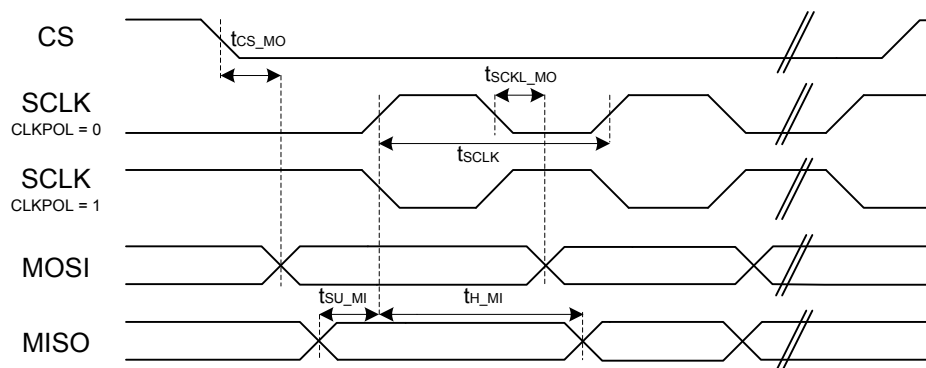


Figure 4.1. SPI Master Timing Diagram

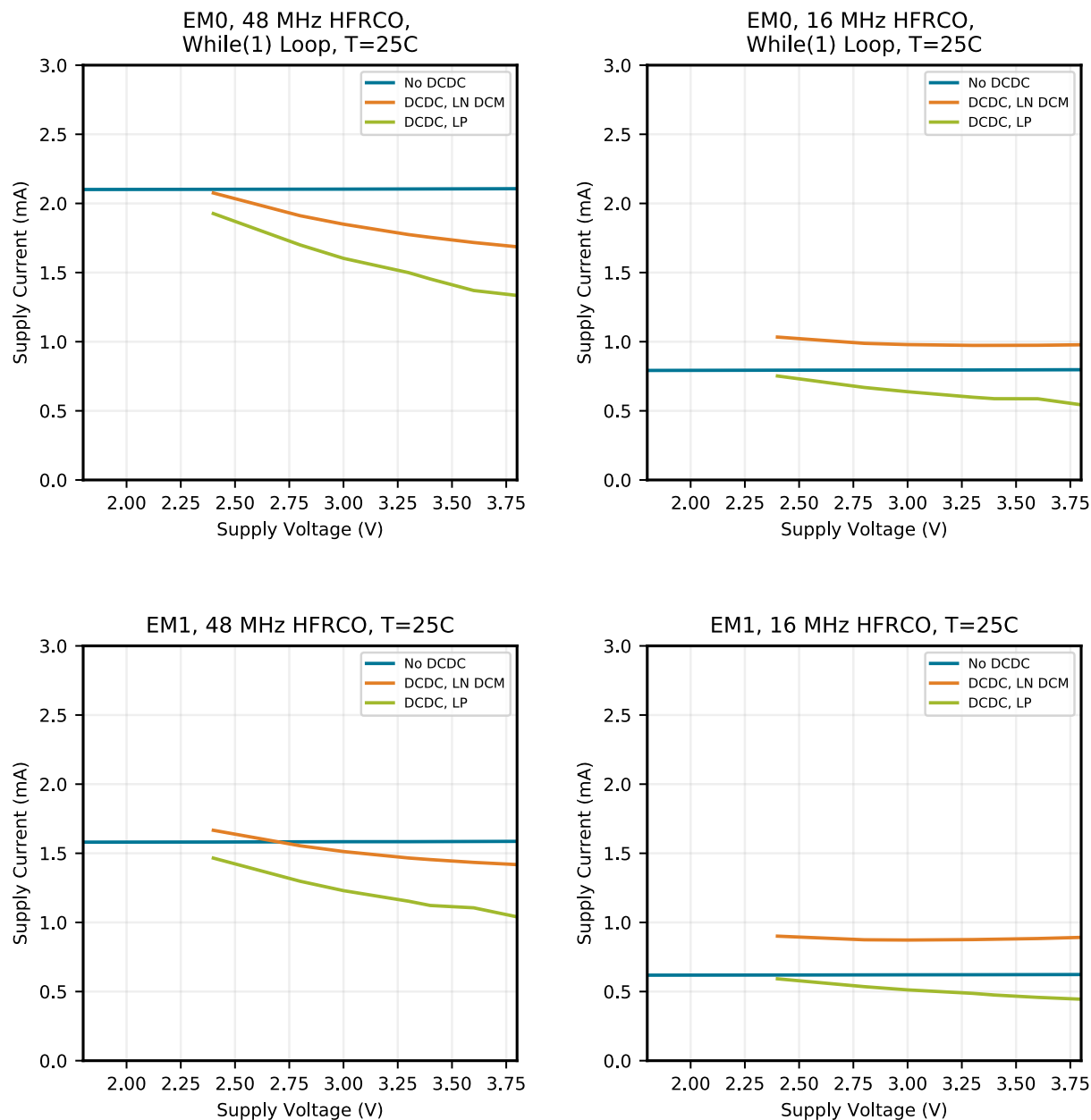


Figure 4.6. EM0 and EM1 Mode Typical Supply Current vs. Supply

Typical supply current for EM2, EM3 and EM4H using standard software libraries from Silicon Laboratories.

5.13 EFM32TG11B1xx in QFN32 Device Pinout

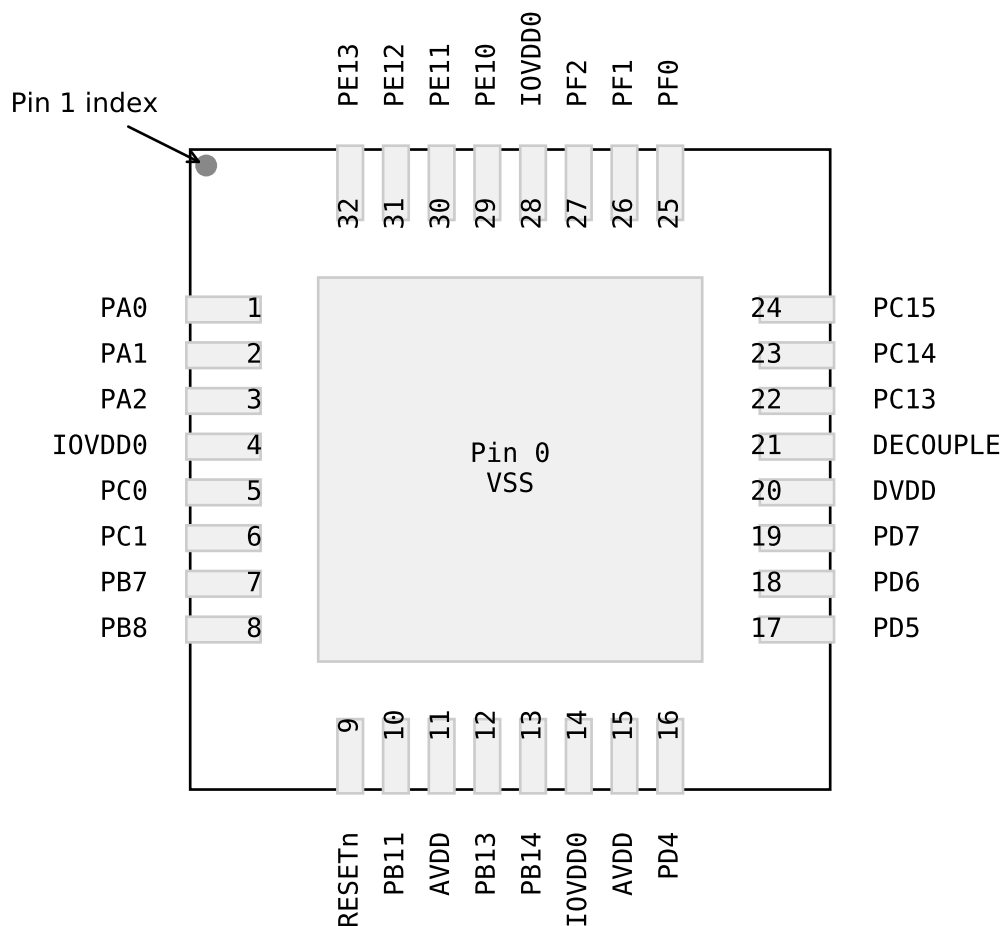


Figure 5.13. EFM32TG11B1xx in QFN32 Device Pinout

The following table provides package pin connections and general descriptions of pin functionality. For detailed information on the supported features for each GPIO pin, see [5.14 GPIO Functionality Table](#) or [5.15 Alternate Functionality Overview](#).

Table 5.13. EFM32TG11B1xx in QFN32 Device Pinout

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
VREGVSS	0	Voltage regulator VSS	PA0	1	GPIO
PA1	2	GPIO	PA2	3	GPIO
IOVDD0	4 14 28	Digital IO power supply 0.	PC0	5	GPIO (5V)
PC1	6	GPIO (5V)	PB7	7	GPIO

5.14 GPIO Functionality Table

A wide selection of alternate functionality is available for multiplexing to various pins. The following table shows the name of each GPIO pin, followed by the functionality available on that pin. Refer to [5.15 Alternate Functionality Overview](#) for a list of GPIO locations available for each function.

Table 5.14. GPIO Functionality Table

GPIO Name	Pin Alternate Functionality / Description			
	Analog	Timers	Communication	Other
PA0	BUSBY BUSAX LCD_SEG13	TIM0_CC0 #0 TIM0_CC1 #7 PCNT0_S0IN #4	US1_RX #5 US3_TX #0 LEU0_RX #4 I2C0_SDA #0	CMU_CLK2 #0 PRS_CH0 #0 PRS_CH3 #3 GPIO_EM4WU0
PA1	BUSAY BUSBX LCD_SEG14	TIM0_CC0 #7 TIM0_CC1 #0 PCNT0_S1IN #4	US3_RX #0 I2C0_SCL #0	CMU_CLK1 #0 PRS_CH1 #0
PA2	BUSBY BUSAX LCD_SEG15	TIM0_CC2 #0	US1_RX #6 US3_CLK #0	CMU_CLK0 #0
PA3	BUSAY BUSBX LCD_SEG16	TIM0_CDTI0 #0	US3_CS #0 U0_TX #2	CMU_CLK2 #1 CMU_CLK2 #4 CMU_CLKI0 #1 LES_AL- TEX2
PA4	BUSBY BUSAX LCD_SEG17	TIM0_CDTI1 #0	US3_CTS #0 U0_RX #2	LES_ALTEX3
PA5	BUSAY BUSBX LCD_SEG18	TIM0_CDTI2 #0	US3_RTS #0 U0_CTS #2	LES_ALTEX4 ACMP1_O #7
PA6	BUSBY BUSAX LCD_SEG19	WTIM0_CC0 #1	U0_RTS #2	PRS_CH6 #0 ACMP0_O #4 GPIO_EM4WU1
PB3	BUSAY BUSBX LCD_SEG20 / LCD_COM4	TIM1_CC3 #2 WTIM0_CC0 #6	US2_TX #1 US3_TX #2	ACMP0_O #7
PB4	BUSBY BUSAX LCD_SEG21 / LCD_COM5	WTIM0_CC1 #6	US2_RX #1	
PB5	BUSAY BUSBX LCD_SEG22 / LCD_COM6	WTIM0_CC2 #6 PCNT0_S0IN #6	US0_RTS #4 US2_CLK #1	
PB6	BUSBY BUSAX LCD_SEG23 / LCD_COM7	TIM0_CC0 #3 PCNT0_S1IN #6	US0_CTS #4 US2_CS #1	
PC0	VDAC0_OUT0ALT / OPA0_OUTALT #0 BU- SACMP0Y BUSACMP0X	TIM0_CC1 #3 PCNT0_S0IN #2	CAN0_RX #0 US0_TX #5 US1_TX #0 US1_CS #4 US2_RTS #0 US3_CS #3 I2C0_SDA #4	LES_CH0 PRS_CH2 #0
PC1	VDAC0_OUT0ALT / OPA0_OUTALT #1 BU- SACMP0Y BUSACMP0X	TIM0_CC2 #3 WTIM0_CC0 #7 PCNT0_S1IN #2	CAN0_TX #0 US0_RX #5 US1_TX #4 US1_RX #0 US2_CTS #0 US3_RTS #1 I2C0_SCL #4	LES_CH1 PRS_CH3 #0
PC2	VDAC0_OUT0ALT / OPA0_OUTALT #2 BU- SACMP0Y BUSACMP0X	TIM0_CDTI0 #3 WTIM0_CC1 #7	US1_RX #4 US2_TX #0	LES_CH2
PC3	VDAC0_OUT0ALT / OPA0_OUTALT #3 BU- SACMP0Y BUSACMP0X	TIM0_CDTI1 #3 WTIM0_CC2 #7	US1_CLK #4 US2_RX #0	LES_CH3

Port	Bus	CH31	CH30	CH29	CH28	CH27	CH26	CH25	CH24	CH23	CH22	CH21	CH20	CH19	CH18	CH17	CH16	CH15	CH14	CH13	CH12	CH11	CH10	CH9	CH8	CH7	CH6	CH5	CH4	CH3	CH2	CH1	CH0
OPA3_OUT																																	
APORT1Y	APORT2Y	APORT3Y	APORT4Y	BUSDY	BUSCY	BUSBY	BUSAY																										

6.2 TQFP80 PCB Land Pattern

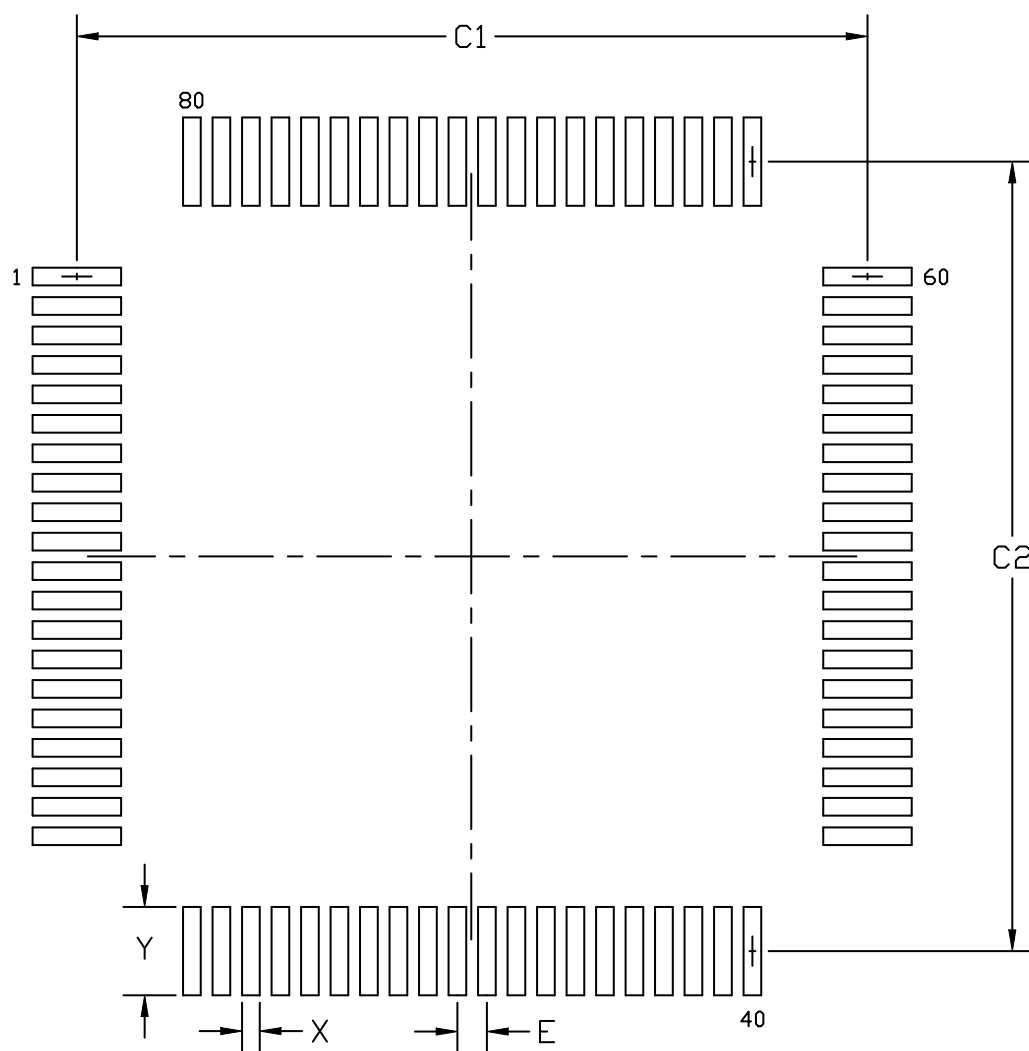


Figure 6.2. TQFP80 PCB Land Pattern Drawing

Table 6.2. TQFP80 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	13.30	13.40
C2	13.30	13.40
E	0.50 BSC	
X	0.20	0.30
Y	1.40	1.50

- Note:**
- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
 - 2. This Land Pattern Design is based on the IPC-7351 guidelines.
 - 3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.
 - 4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
 - 5. The stencil thickness should be 0.125 mm (5 mils).
 - 6. The ratio of stencil aperture to land pad size can be 1:1 for all pads.
 - 7. A No-Clean, Type-3 solder paste is recommended.
 - 8. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

6.3 TQFP80 Package Marking



Figure 6.3. TQFP80 Package Marking

- The package marking consists of:
- P – The part number designation.
 - T – A trace or manufacturing code. The first letter is the device revision.
 - Y – The last 2 digits of the assembly year.
 - W – The 2-digit workweek when the device was assembled.

7.2 QFN80 PCB Land Pattern

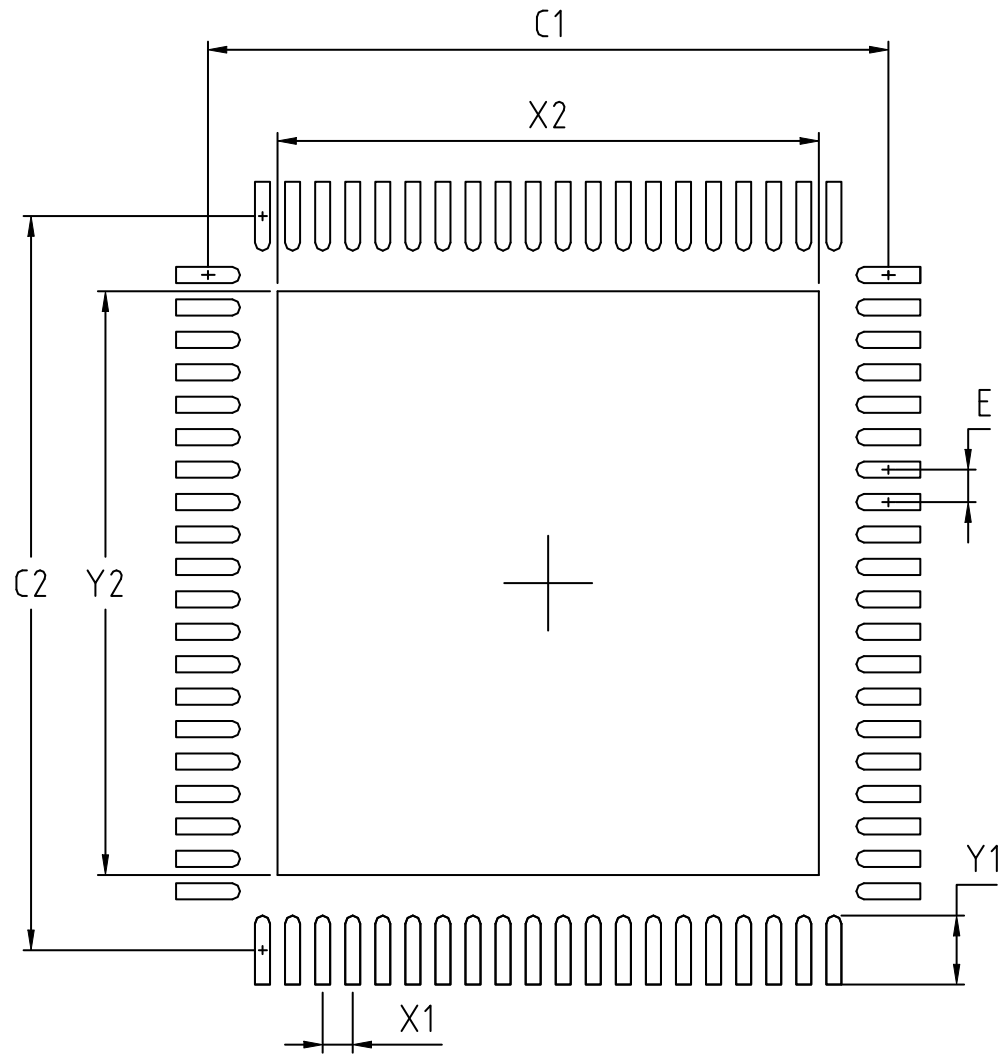


Figure 7.2. QFN80 PCB Land Pattern Drawing

7.3 QFN80 Package Marking



Figure 7.3. QFN80 Package Marking

The package marking consists of:

- P P P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code. The first letter is the device revision.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.

8. TQFP64 Package Specifications

8.1 TQFP64 Package Dimensions

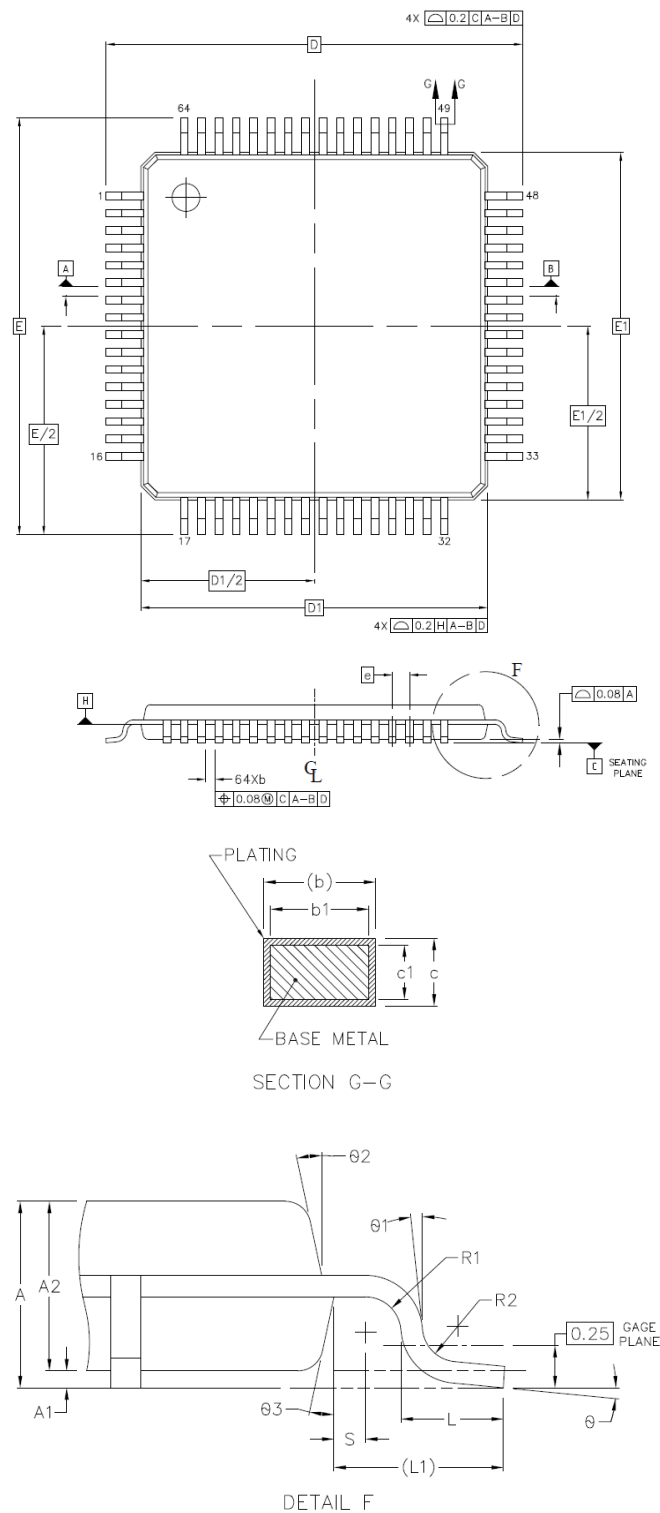


Figure 8.1. TQFP64 Package Drawing

10.3 TQFP48 Package Marking



Figure 10.3. TQFP48 Package Marking

The package marking consists of:

- P P P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code. The first letter is the device revision.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.

11.3 QFN32 Package Marking



Figure 11.3. QFN32 Package Marking

The package marking consists of:

- P P P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code. The first letter is the device revision.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.